

Session Program

25-28 Jun 2006

8th RD50 Workshop

Defect and Material Characterization

Prague

Monday 26 June

09:20

Defect and Material Characterization

Session | Location: Prague

09:20-09:40

Defect kinetics in Epi/Cz silicon after Co60-gamma irradiation

Speaker

Ioana Pintilie

09:40-10:00

Characterization of irradiated silicon structures by microwave absorption techniques

Speaker

Eugenijus Gaubas

10:00-10:30

Coffee break

10:30-10:50

DLTS measurements of Epitaxial and MCZ silicon detectors after 26 MeV proton irradiation

Speaker

Frank Hoeniger

10:50-11:20

Discussion on Defect and Material Characterization

11:20